REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Add vendor CAGE number 92527. Pages 4 and 5: Changes in electrical table. Editorial changes throughout.	1988 APR 6	M.A. Frye
B	Add vendor CAGE 95569 for device type 01. Add device type 02. Delete vendor CAGE 92527. Add case outline S for device types 01 and 02. Editorial changes throughout.	1989 APR 11	M.A. Frye
C	Add vendor CAGE 9Z527 for device type 01. Add vendor CAGE 27014 for device type 01. Add vendor CAGE 75569 to device type 02. Technical changes in table I. Editorial changes throughout.	1989 DEC 7	M.A. Frye

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REV STATUS OF SHEETS	REV	C	C	C	C	C	C	C	C	C	C	C	C	C	C										
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14										

PMIC N/A

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DRAWING APPROVAL DATE: 6 NOVEMBER 1987

REVISION LEVEL: C

STANDARDIZED MILITARY DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

MICROCIRCUITS, DIGITAL, FAST CMOS, NONINVERTING OCTAL BUS TRANSCEIVER, THREE-STATE, MONOLITHIC SILICON

SIZE	CAGE CODE	
A	67268	5962-87629

SHEET OF 1

DESC FORM 193
SEP 87

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5962-E1484

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-87629	01	R	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device types. The device types shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54FCT245	Octal, three-state, noninverting, bus transceiver, TTL compatible
02	54FCT245A	Octal, three-state, noninverting, bus transceiver, TTL compatible

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
R	D-8 (20-lead, 1.060" x .310" x .200"), dual-in-line package
S	F-9 (20-lead, .540" x .300" x .100"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings. 1/

Supply voltage range	-0.5 V dc to +6.0 V dc
Input voltage range	-0.5 V dc to V_{CC} + 0.5 V dc
Output voltage range	-0.5 V dc to V_{CC} + 0.5 V dc
I/O voltage range	-0.5 V dc to V_{CC} + 0.5 V dc
DC input diode current (I_{IK})	-20 mA
DC output diode current (I_{OK})	-50 mA
DC output current	±100 mA
Maximum power dissipation (P_D) 2/	500 mW
Thermal resistance, junction-to-case (θ_{JC})	See MIL-M-38510, appendix C
Storage temperature range	-65°C to +150°C
Junction temperature (T_J)	+175°C
Lead temperature (soldering, 10 seconds)	+300°C

1.4 Recommended operating conditions.

Supply voltage range (V_{CC})	+4.5 V dc to +5.5 V dc
Maximum low level input voltage (V_{IL})	0.8 V dc
Minimum high level input voltage (V_{IH})	2.0 V dc
Case operating temperature range (T_C)	-55°C to +125°C

1/ All voltages referenced to GND.
2/ Must withstand the added P_D due to short circuit test, e.g.; I_{OS}.

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ V_{CC} = 5.0 V dc ±10% unless otherwise specified		Device types	Group A subgroups	Limits		Unit
						Min	Max	
High level output voltage	V_{OH1}	V_{CC} = 4.5 V V_{IL} = 0.8 V V_{IH} = 2.0 V	I_O = -300µA	All	1, 2, 3	4.3		V
	V_{OH2}		I_O = -12 mA		1, 2, 3	2.4		
Low level output voltage (port A)	V_{OL1}	V_{CC} = 4.5 V V_{IL} = 0.8 V V_{IH} = 2.0 V	I_O = 300 µA	All	1, 2, 3		0.2	V
	V_{OL2}		I_O = 48 mA		1, 2, 3		0.55	
Low level output voltage (port B)	V_{OL3}	V_{CC} = 4.5 V V_{IL} = 0.8 V V_{IH} = 2.0 V	I_O = 300 µA	All	1, 2, 3		0.2	V
	V_{OL4}		I_O = 48 mA		1, 2, 3		0.55	
Input clamp voltage	V_{IK}	V_{CC} = 4.5 V, I_{IN} = -18 mA		All	1		-1.2	V
High level input current	I_{IH1}	V_{CC} = 5.5 V, V_{IN} = 5.5 V		All	1, 2, 3		5.0	µA
Low level input current	I_{IL1}	V_{CC} = 5.5 V, V_{IN} = GND		All	1, 2, 3		-5.0	µA
High level input current for common I/O pins	I_{IH2}	V_{CC} = 5.5 V, V_{IN} = 5.5 V		All	1, 2, 3		20	µA
Low level input current for common I/O pins	I_{IL2}	V_{CC} = 5.5 V, V_{IN} = GND		All	1, 2, 3		-20	µA
Short circuit output current	I_{OS}	V_{CC} = 5.5 V 1/		All	1, 2, 3	-60		mA
Quiescent power supply current (CMOS inputs)	I_{CCQ}	$V_{IN} \le 0.2$ V or $V_{IN} \ge 5.3$ V, V_{CC} = 5.5 V, f_I = 0 MHz		All	1, 2, 3		1.5	mA

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$, V_{CC} = 5.0 V dc ±10% unless otherwise specified	Device types	Group A subgroups	Limits Min	Limits Max	Unit
Quiescent power supply current (TTL inputs)	ΔI_{CC}	V_{CC} = 5.5 V, V_{IN} = 3.4 V 2/	All	1, 2, 3		2.0	mA
Dynamic power supply current	I_{CCD}	V_{CC} = 5.5 V, Outputs open, $T/\overline{R}$ = V_{CC}, One bit toggling - 50% duty cycle $V_{IN} \ge 5.3$ V or $V_{IN} \le 0.2$ V $\overline{OE}$ = GND	All	3/		0.4	mA/MHz
Total power supply current 4/	I_{CC}	$V_{IN} \ge 5.3$ V or $V_{IN} \le 0.2$ V, V_{CC} = 5.5 V, f_I = 10 MHz, Outputs open, One bit toggling - 50% duty cycle $T/\overline{R}$ = $\overline{OE}$ = GND	All	1, 2, 3		5.5	mA
		V_{IN} = 3.4 V or V_{IN} = GND, V_{CC} = 5.5 V, f_I = 10 MHz, Outputs open, One bit toggling = 50% duty cycle $T/\overline{R}$ = $\overline{OE}$ = GND	All	1, 2, 3		6.0	mA
Functional tests		See 4.3.1c	All	7, 8			
Input capacitance	C_{IN}	See 4.3.1d	All	4		10	pF
Output capacitance	C_{OUT}	See 4.3.1d	All	4		12	pF
Propagation delay time, inputs to outputs	t_{PLH}, t_{PHL}	C_L = 50 pF, R_L = 500Ω, See figure 4 5/	01	9, 10, 11	1.5	7.5	ns
			02	9, 10, 11	1.5	4.9	
Output enable time, $\overline{OE}$ to A_n or B_n	t_{PZH}, t_{PZL}		01	9, 10, 11	1.5	10.0	ns
			02	9, 10, 11	1.5	6.5	
Output disable time, $\overline{OE}$ to A_n or B_n	t_{PHZ}, t_{PLZ}		01	9, 10, 11	1.5	10.0	ns
			02	9, 10, 11	1.5	6.0	

See footnotes at top of next page.

1/ Not more than one output should be shorted at one time, and the duration of the short circuit condition should not exceed 1 second.
2/ TTL driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND.
3/ This parameter is not directly testable, but is derived for use in total power supply calculations.
4/ $I_{CC} = I_{CCQ} + (\Delta I_{CC} \times D_H \times N_T) + (I_{CCD} \times f_I \times N_I)$
Where: D_H = Duty cycle for TTL inputs high
N_T = Number of TTL inputs at D_H
f_I = Input frequency in MHZ
N_I = Number of inputs at f_I
5/ The minimum limits are guaranteed, if not tested, to the specified limits.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

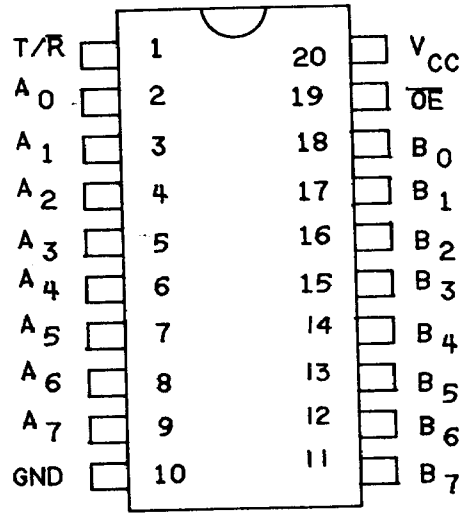
3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

Device types 01 and 02

Cases R and S



Case 2

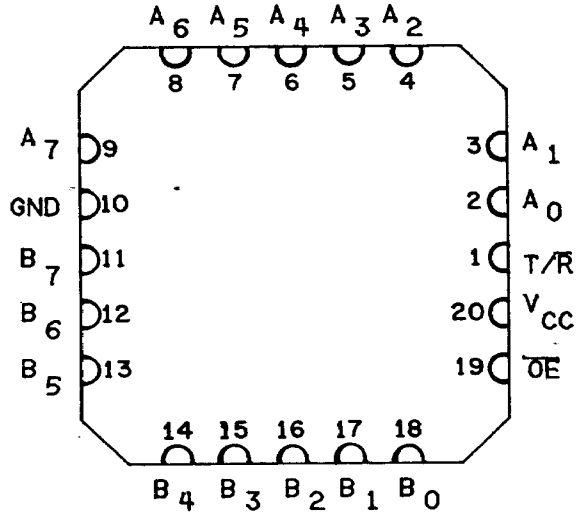


FIGURE 1. Terminal connections.

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Device types 01 and 02

Inputs		Outputs
$\overline{OE}$	T/$\overline{R}$	
L	L	Bus B data to Bus A
L	H	Bus A data to Bus B
H	X	Z

L = Low voltage level
H = High voltage level
X = Immaterial
Z = High impedance state

FIGURE 2. Truth table.

Device types 01 and 02

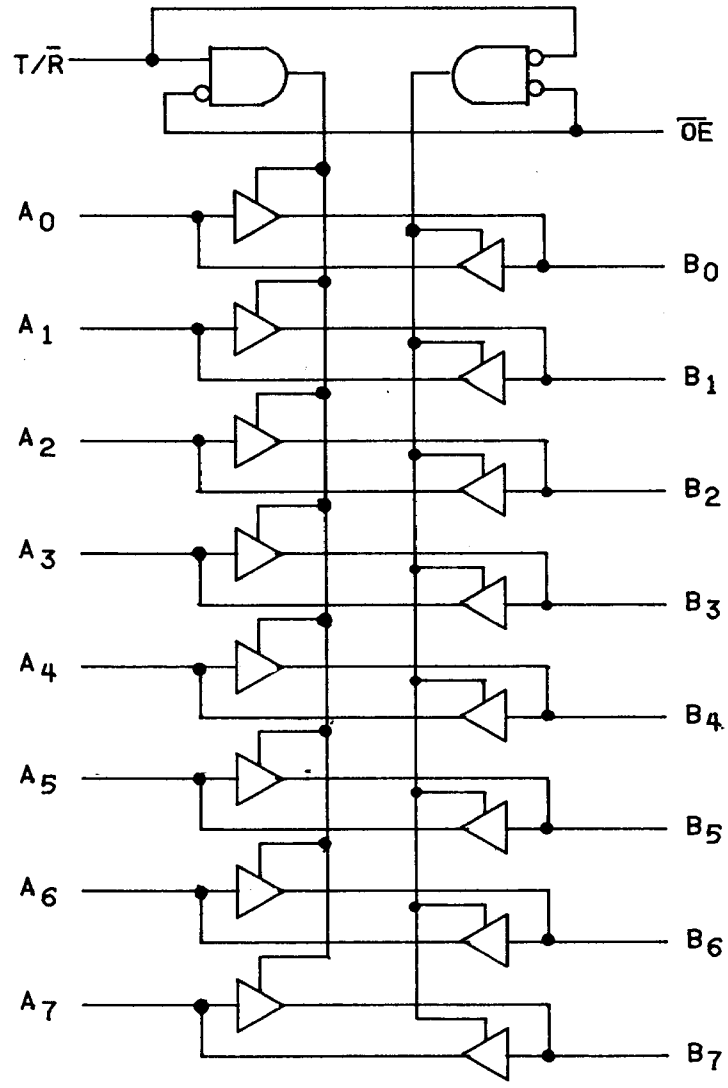
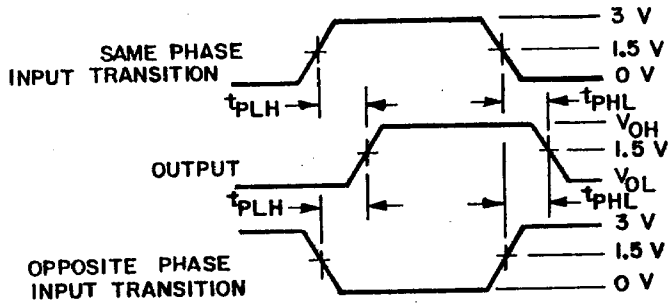


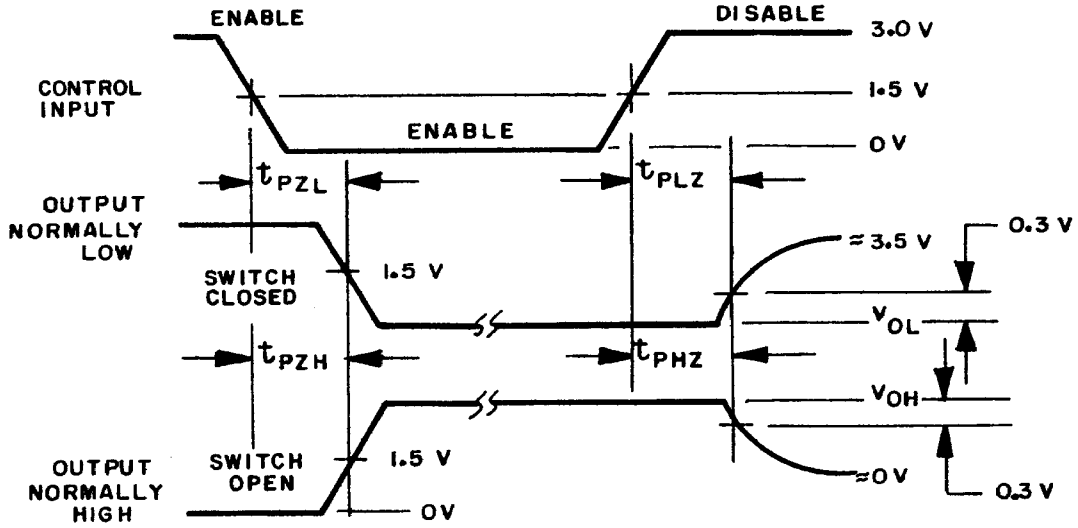
FIGURE 3. Logic diagram.

Device types 01 and 02

PROPAGATION DELAY



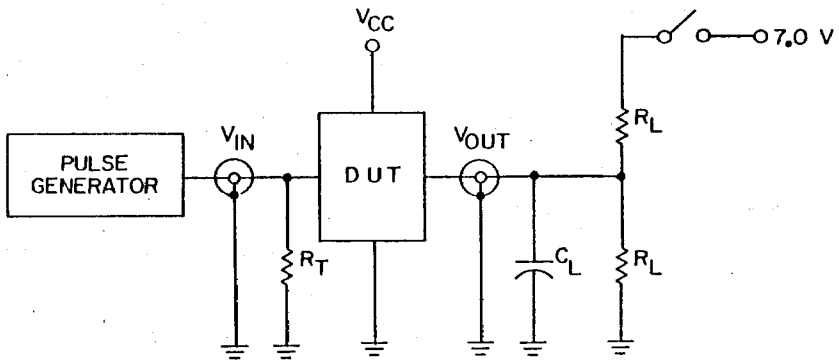
ENABLE AND DISABLE TIMES



NOTES:
1. Diagram shown for input control enable - low and input control disable - high.
2. Pulse generatore for all pulses: $t_f \leq 2.5$ ns: $t_r \leq 2.5$ ns.

FIGURE 4. Switching waveforms and test circuit.

TEST CIRCUIT FOR THREE-STATE OUTPUTS



Switch position

Test	Switch
t_{PLZ}	Closed
t_{PZL}	Closed
All other	Open

Definitions:
R_L = Load resistor see ac characteristics for value.
C_L = Load capacitance includes jig and probe capacitance:
See ac chacteristics for value.
R_T = Termination should be equal to Z_{OUT} of pulse generators.

FIGURE 4. Switching waveforms and test circuit - Continued.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2.

d. Subgroup 4 (C_{IN} and C_{OUT} measurements) shall be measured only initially and after process or design changes which may affect capacitance. Test all applicable pins on five devices with zero failures.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) T_A = +125°C, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved sources of supply listed below are for information purposes only and are current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/
5962-8762901RX	27014	54FCT245DMQB
	61772	IDT54FCT245DB
	75569	P54PCT245DMB
	9Z527	VJ54FCT245D
5962-8762901SX	27014	54FCT245FMQB
	61772	IDT54FCT245EB
	75569	P54PCT245FMB
5962-87629012X	27014	54FCT245LMQB
	61772	IDT54FCT245LB
	75569	P54PCT245LMB
	9Z527	VJ54FCT245DL
5962-8762902RX	61772	IDT54FCT245ADB
	75569	P54PCT245ADMB
5962-8762902SX	61772	IDT54FCT245AEB
	75569	P54PCT245AFMB
5962-87629022X	61772	IDT54FCT245ALB
	75569	P54PCT245ALMB

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
27014	National Semiconductor 333 Western Avenue South Portland, ME 04106
61772	Integrated Device Technology 3236 Scott Boulevard Santa Clara, CA 95052
75569	Performance Semiconductor Corporation 610 E. Weddell Drive Sunnyvale, CA 94089
9Z527	VTC Incorporated 2401 E. 86th Street Bloomington, MN 55425

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